

### 80N03F-VB Datasheet

## N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a, e</sup>	Q <sub>g</sub> (Typ.)		
30	0.003 at V <sub>GS</sub> = 10 V	120	71 nC		
30	$0.005$ at $V_{GS} = 4.5 \text{ V}$	90	71110		

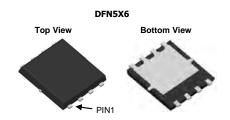
#### **FEATURES**

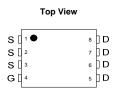
- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested

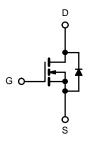


#### **APPLICATIONS**

- Notebook PC Core
- VRM/POL







N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V		
Gate-Source Voltage		V <sub>GS</sub>	± 20	7 v	
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>C</sub> = 25 °C		120 <sup>a, e</sup>		
	T <sub>C</sub> = 70 °C	1-	90 <sup>e</sup>		
	T <sub>A</sub> = 25 °C	I <sub>D</sub>	21 <sup>b, c</sup>	A	
	T <sub>A</sub> = 70 °C		20.8 <sup>b, c</sup>	^	
Pulsed Drain Current		I <sub>DM</sub>	250	7	
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	56		
Single Pulse Avalanche Energy	L = 0.1 IIII	E <sub>AS</sub>	60	mJ	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	80 <sup>a, e</sup>	A	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	'S	76 <sup>b, c</sup>	^	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		210 <sup>a</sup>		
	T <sub>C</sub> = 70 °C	P <sub>D</sub>	155	w	
	T <sub>A</sub> = 25 °C	' D	35 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		13 <sup>b, c</sup>		
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	41	50	°C/W	
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.7	0.9		

#### Notes:

- a. Based on T<sub>C</sub> = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 µA		35		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 5.5			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	80			Α	
Drain-Source On-State Resistance <sup>a</sup>	Б	$V_{GS} = 10 \text{ V}, I_D = 32 \text{ A}$		0.003		Ω	
	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 29 \text{ A}$		0.005			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 32 A		130		S	
Dynamic <sup>b</sup>						•	
Input Capacitance	C <sub>iss</sub>				3200	pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 12.5 V, $V_{GS}$ = 0 V, f = 1 MHz			1025		
Reverse Transfer Capacitance	C <sub>rss</sub>				970		
Total Gate Charge	Q <sub>g</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 32 \text{ A}$			71	nC	
					61.5		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 29 \text{ A}$			34		
Gate-Drain Charge	$Q_{gd}$				29		
Gate Resistance	R <sub>g</sub>	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			18	27	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.555 $\Omega$		11	17		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ 27 A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		70	105		
Fall Time	t <sub>f</sub>			10	15		
Turn-On Delay Time	t <sub>d(on)</sub>			55	83		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 0.625 $\Omega$		180	270		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 24$ A, $V_{GEN}=4.5$ V, $R_g=1$ $\Omega$		55	83		
Fall Time	t <sub>f</sub>			12	18		
<b>Drain-Source Body Diode Characteristic</b>	es					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	$T_C = 25  ^{\circ}C$			80	Δ	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				100	- A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			52	78	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 20 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t <sub>a</sub>			27		1	
Reverse Recovery Rise Time	t <sub>b</sub>			25		ns	

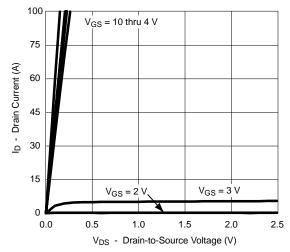
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

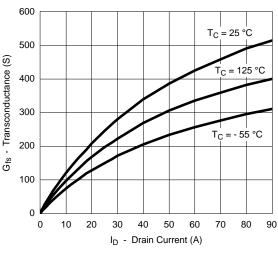
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



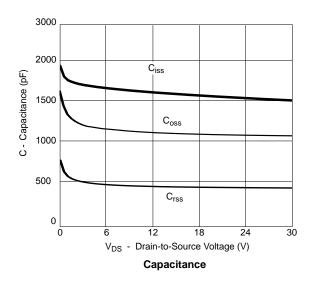
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

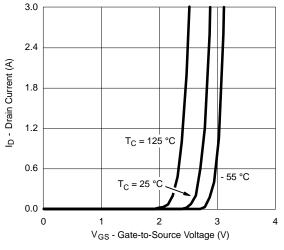


#### **Output Characteristics**

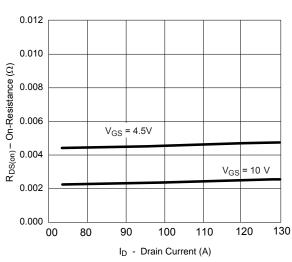


#### Transconductance

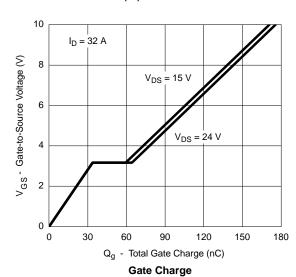




#### **Transfer Characteristics**

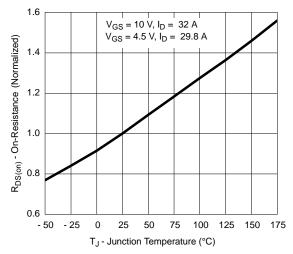


R<sub>DS(on)</sub> vs. Drain Current

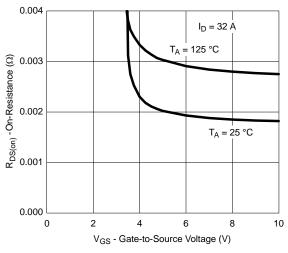




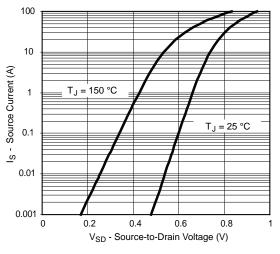
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



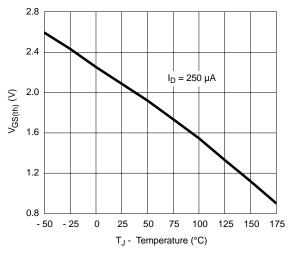
On-Resistance vs. Junction Temperature



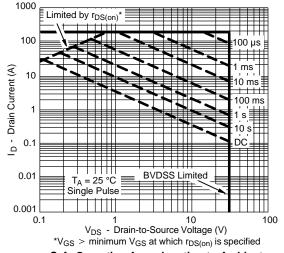
 $\rm R_{\rm DS(on)}$  vs.  $\rm V_{\rm GS}$  vs. Temperature



Forward Diode Voltage vs. Temperature



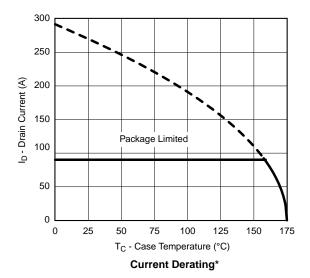
Threshold Voltage

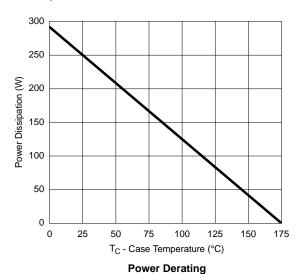


Safe Operating Area, Junction-to-Ambient

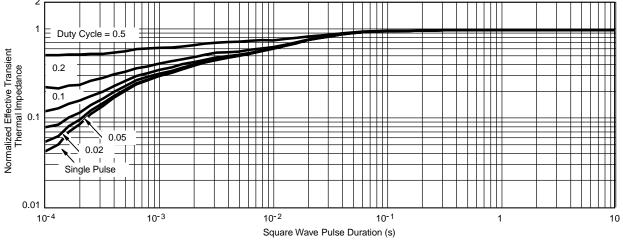


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

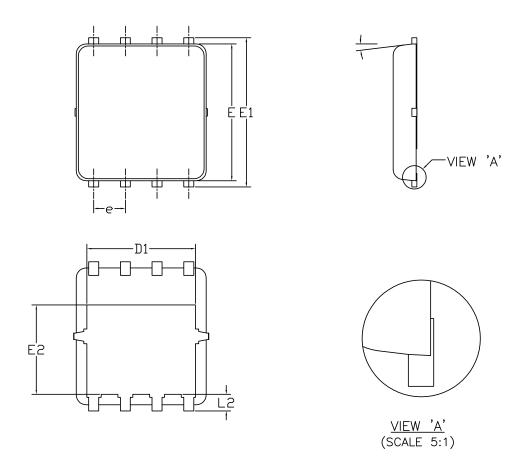


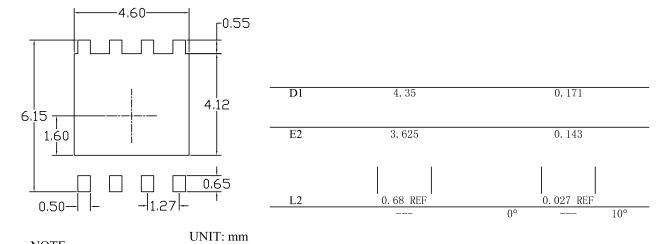


\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case





NOTE 1. PA



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